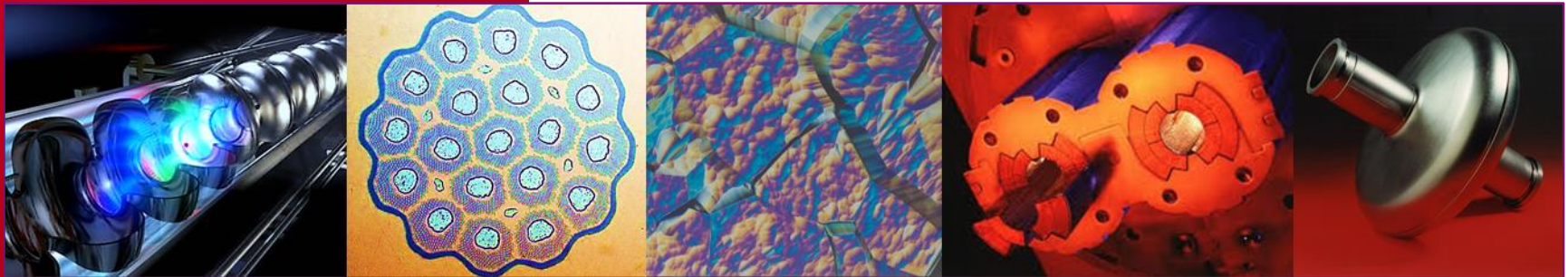


DE LA RECHERCHE À L'INDUSTRIE



(SELECTED) SRF R&D ACTIVITY AT CEA SACLAY



| *SRF group meeting @ KEK*

www.cea.fr

C. Z. ANTOINE (*O. Napoly, F. Eozenou, T. Proslie...*)

Niobium cavities

■ Performances

- $E_{acc} \propto H_{RF}$
- $Q_0 (\propto 1/R_s) \propto T_C \Rightarrow \text{Nb}_3\text{Sn}, \text{MgB}_2, \text{NbN}...$
- Limit = magnetic transition of the SC material @ H_{peak}

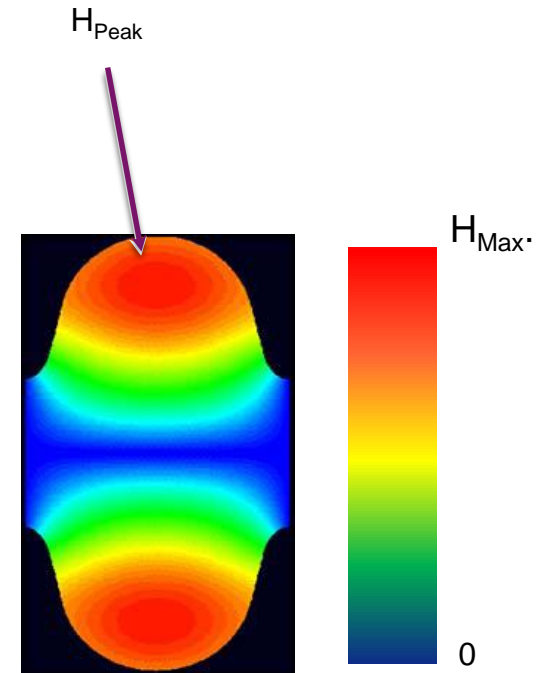
■ Superconductivity only needed inside :

- Thickness $\sim < 1 \mu\text{m} \Rightarrow$ thin films
- (onto a thermally conductive, mechanically resistant material, e.g. Cu)

■ Today :

- Thin films exhibit too many defects
- Only Bulk Nb has high SRF performances

■ Issues : getting “defect free” superconductors (yes but not all defects are detrimental...)



H field mapping in an elliptical cavity

■ SC phase diagram

■ All SC applications except SRF:

mixed state w. vortex

- Vortices dissipate in RF !

■ SRF => Meissner state **mandatory !**

■ H_{C1} = limit Meissner/mixed state

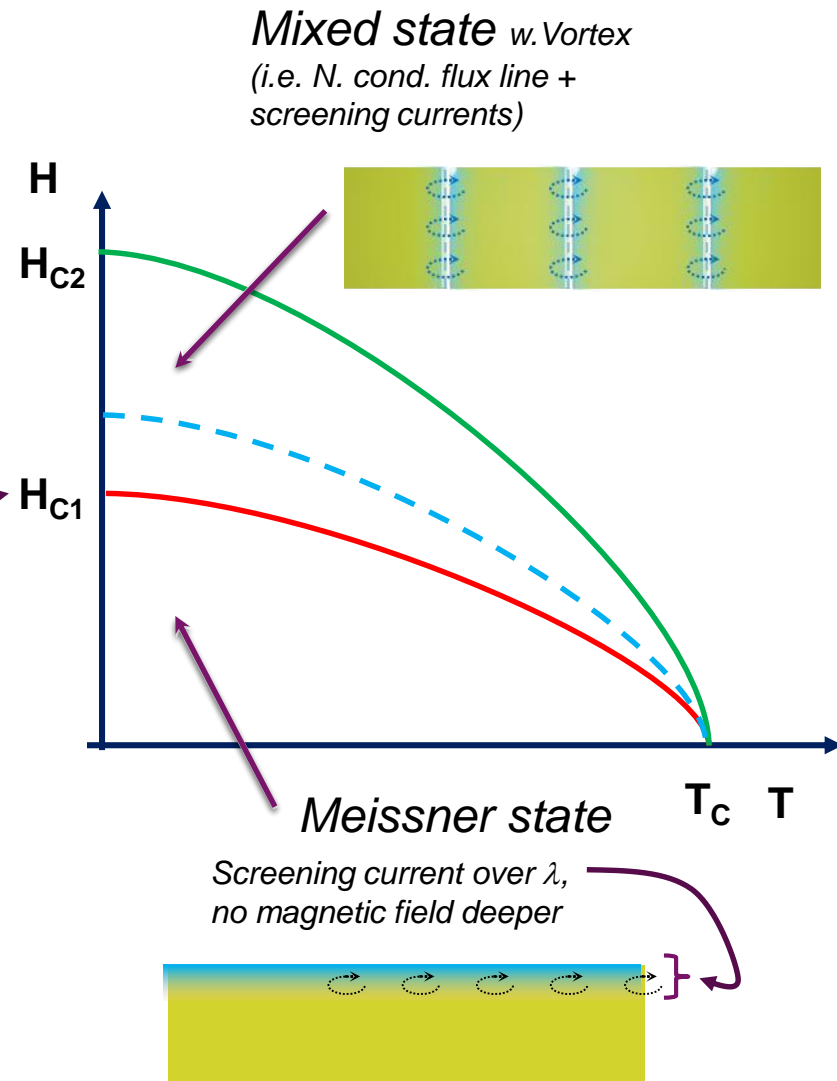
■ Nb: highest H_{C1} (180 mT)

■ “Superheating field”(?) :

Metastable state favored

by $H \parallel$ to surface

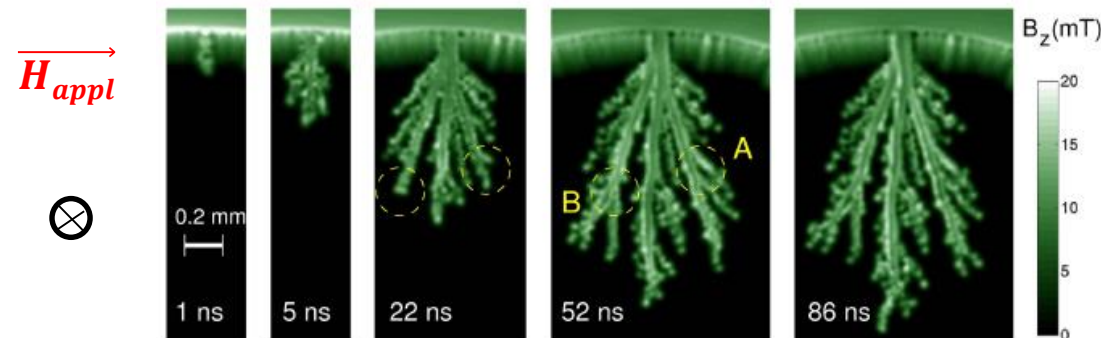
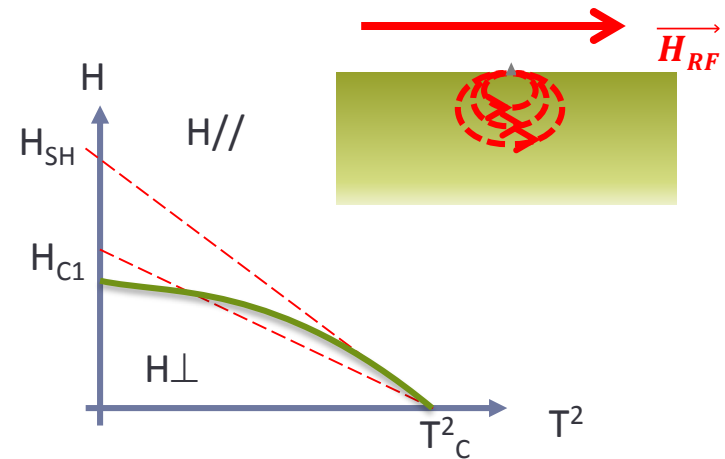
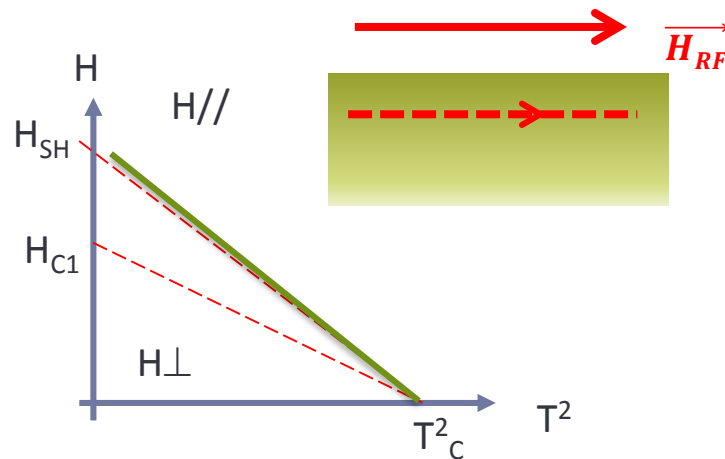
- Difficult to get in real life !



WHAT IS THE LIMIT ($H_P/H_{C1}/H_{SH}$) ?

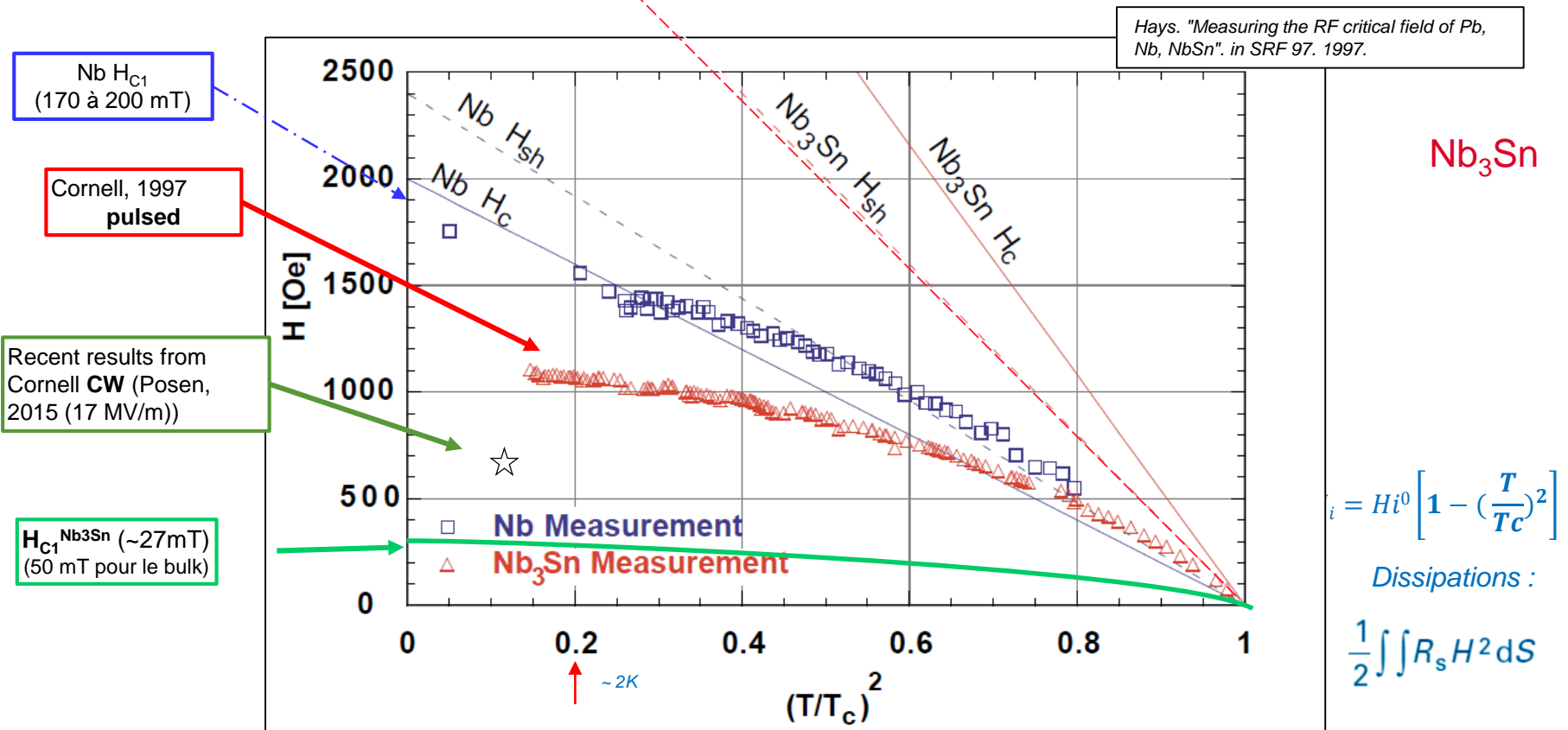


- Real world cavities behavior is dominated by a few number of defects
- It is very important to measure the penetration field of samples in realistic conditions



- $\sim 100 \mu\text{m}$ in 1 ns (\sim RF period)
- Compare with λ (field penetration depth)
 - Nb : $\sim 40 \text{ nm}$
 - MgB₂ $\sim 200 \text{ nm}$
- Avalanche : high RF dissipation

MgB₂:
http://www.nature.com/srep/2012/121126/srep00886/full/srep00886.html?message-global=remove&WT.ec_id=SREP-20121127



■ **Vortices enter more easily at lower temperature (counter intuitive !)?**

- @ $T \sim T_c$: H is low \Rightarrow low dissipations \Rightarrow easy to thermally stabilize
- @ $T \ll T_c$: H is high \Rightarrow even if small defect \Rightarrow high dissipations \Rightarrow Favors flux jumps

=> We have to reduce defect density (yes but which ones?)



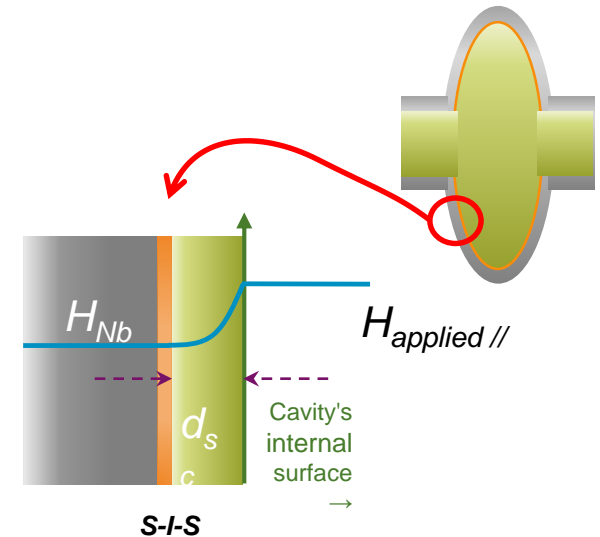
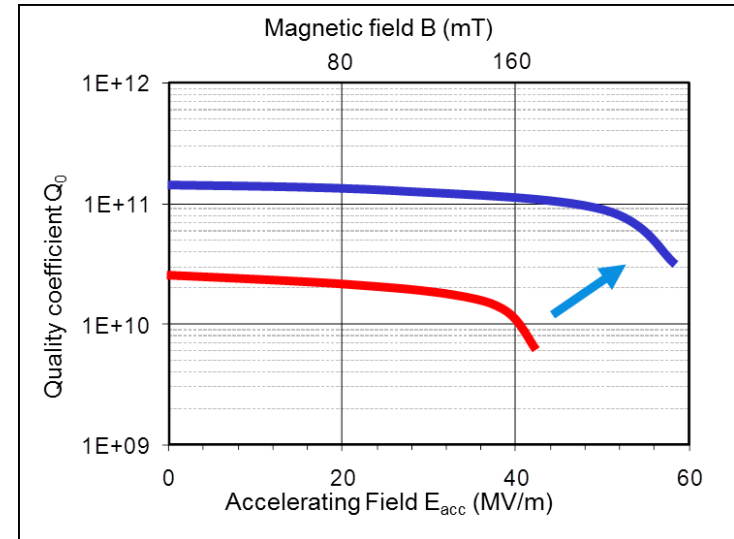
Structures proposed by A. Gurevich in 2006, SRF tailored

■ Dielectric layer

- Small \perp vortex (short \rightarrow low dissipation)
 - Quickly coalesce (w. RF)
 - Blocks avalanche penetration
- \Rightarrow **Multilayer** concept for RF application

■ Nanometric I/S// layers deposited on Nb

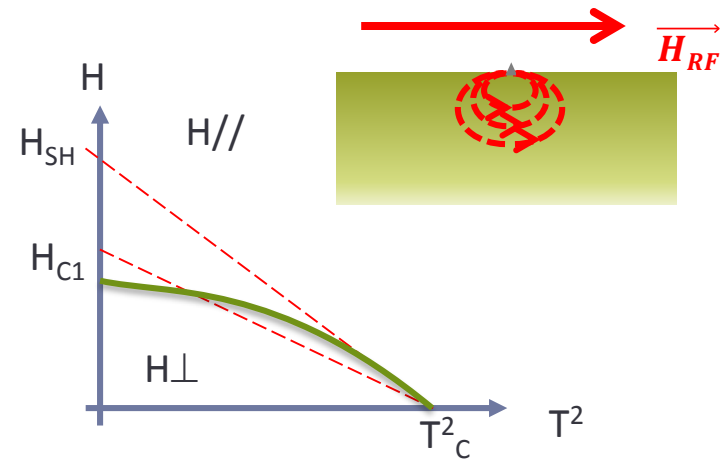
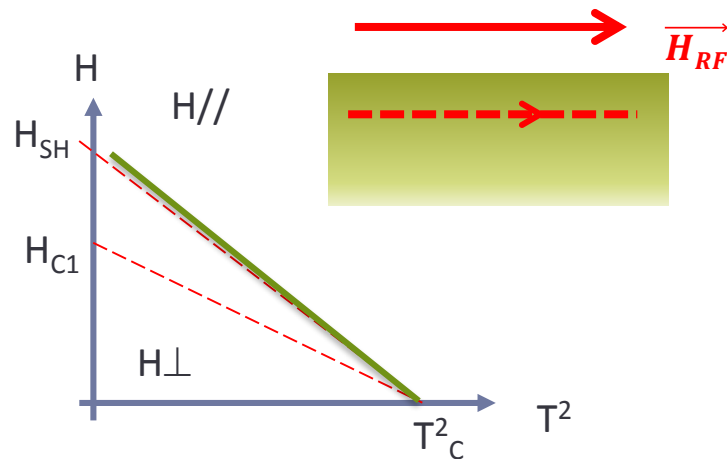
- SC nanometric layers (≤ 100 nm) $\Rightarrow H_{C1} \uparrow \Rightarrow$ Vortex enter at higher field
- Nb surface screening \Rightarrow allows high magnetic field inside the cavity \Rightarrow higher E_{acc}
- SC w. high T_C than Nb (e.g. NbN): $R_s^{NbN} \approx \frac{1}{10} R_s^{Nb}$
 $\Rightarrow Q_0^{multi} \gg Q_0^{Nb}$



WHAT IS THE LIMIT ($H_P/H_{C1}/H_{SH}$) ?

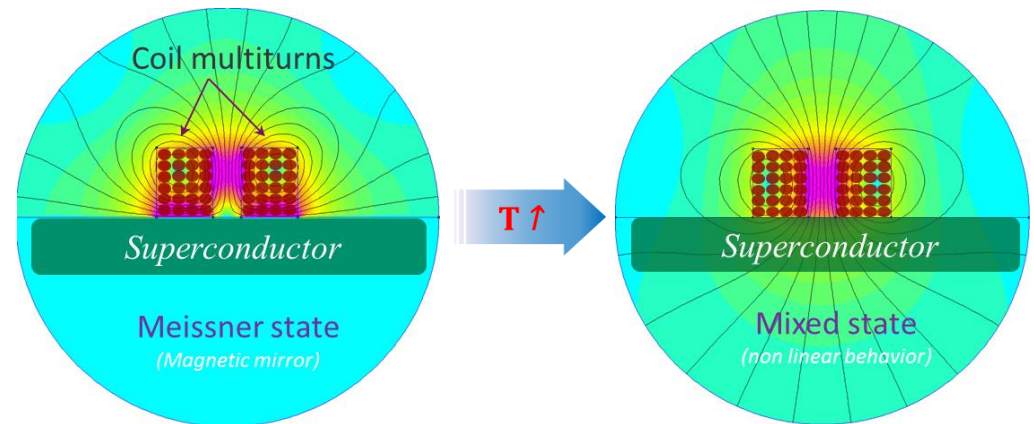


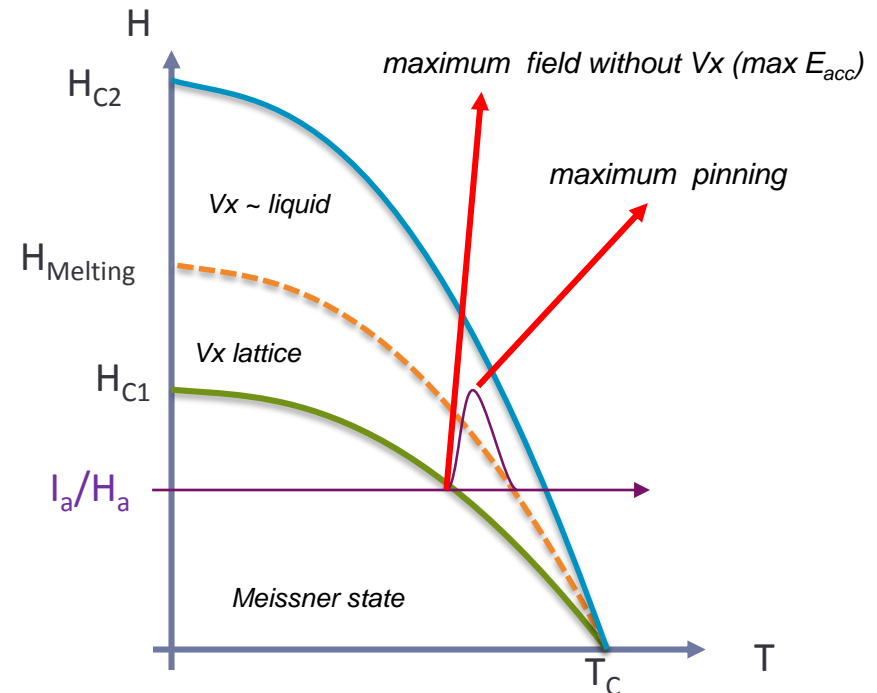
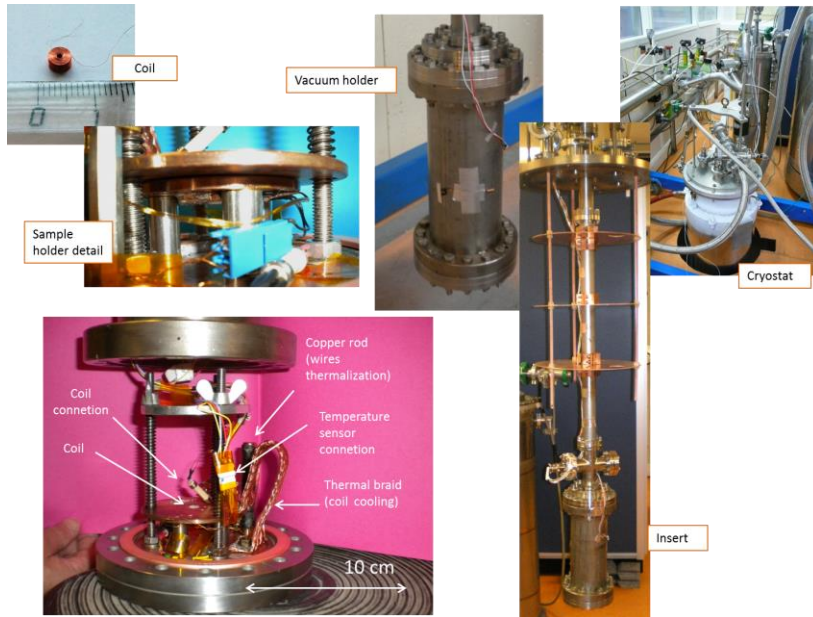
- Real world cavities behavior is dominated by a few number of defects
- It is very important to measure the penetration field of samples in realistic conditions



Local magnetometry

- ~ Same geometry as cavities
- No shape/edge effect (vs DC/ Squid magnetometry)
- No demagnetization effect
- Measures actual penetration field wherever it is $H_P/H_{C1}/H_{SH}$

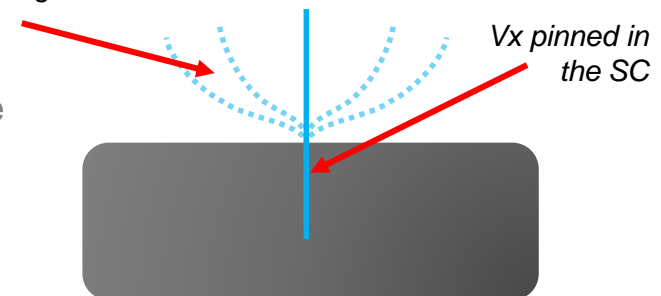




Low frequency \equiv DC :

- $0 < H_a < H_{C1} \Rightarrow R=0$, Meissner state
- $H_{C1} < H_a < H_M \Rightarrow V_x$ are trapped, $R=0$, Campbell regime
- $H_M < H_a < H_{C2} \Rightarrow V_x$ are moving liquid like, $R \neq 0$, Flux flow regime
- Third harmonic signal arise from flux line tension (affects the e- inside the Cu coil),
- It does not depend on dissipation inside Nb, BUT depends on # of V_x trapped there (and length).

flux line moving in AC field



NbN coating by Magnetron Sputtering

■ NbN single layers series

- NbN SL / “thick” Nb layer
 - Magnetron sputtered
 - MgO as dielectric layer
- Far from perfect...



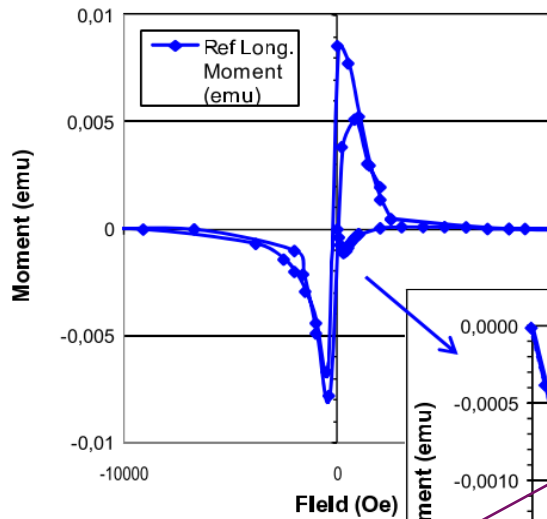
Nb (nm)	MgO (nm) Calc(actual)	NbN (nm) Calc(actual)	T _c (K)
250 [†]	14	0	8.9
250 [†]	14	25	15.5
500	10 (10.3)	50 (65)	15*
500	10 (8.4)	75 (72)	14.1*
500	10 (9.8)	100 (94)	14*
500	10	125	14.3*
500	10 (6.7)	150 (132)	15.9*
500	10 (10.4)	200 (164)	15*

[†] Not same batch, deposited on the same conditions, but substrate = sapphire

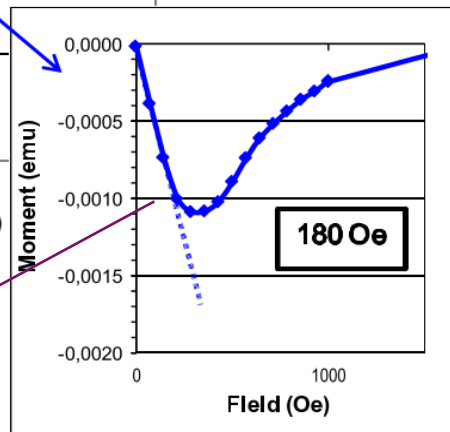
*As determined with magnetometry, see below.

Typical defects...

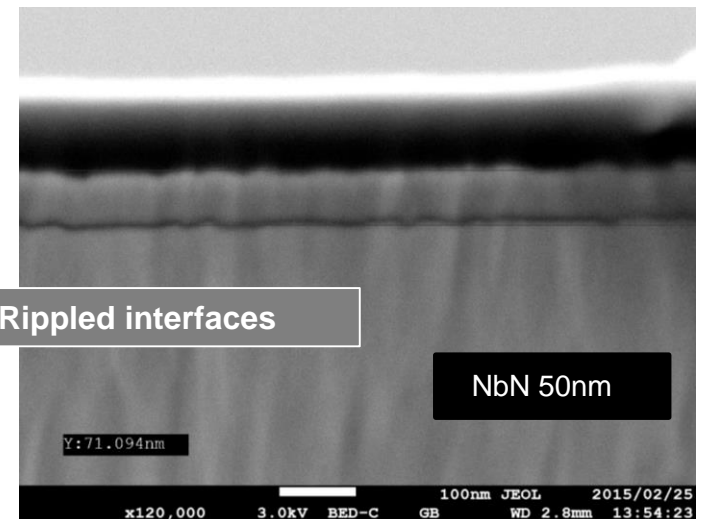
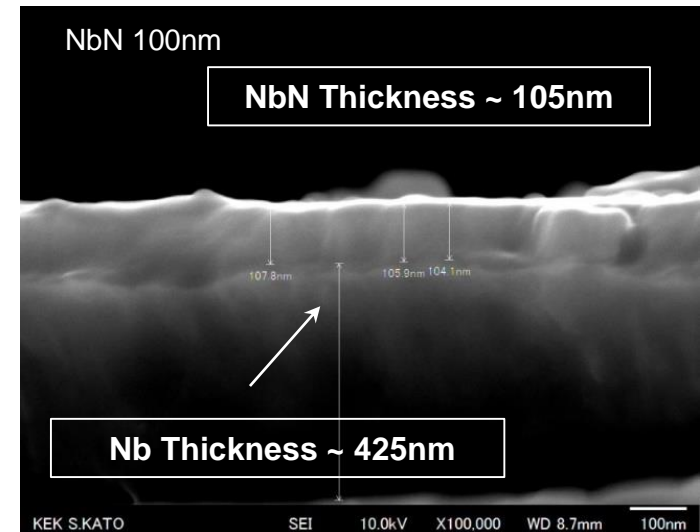
- Low H_{C1}
- Thickness \neq uniform
- ...



250 nm Nb on sapphire
DC Squid magnetometry @ 4.5 K

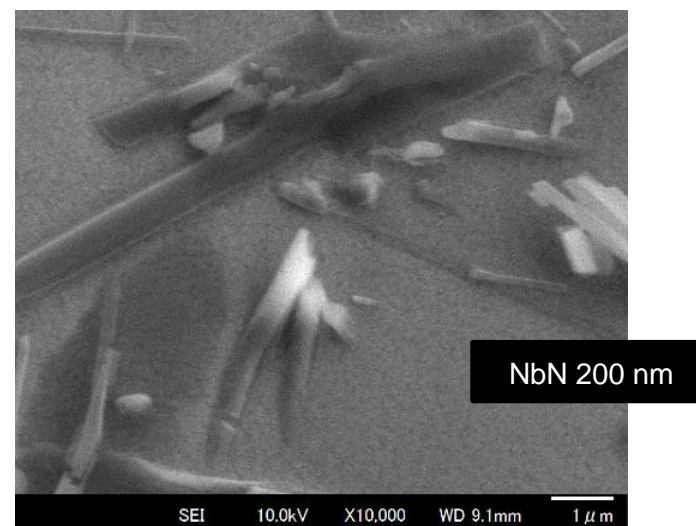
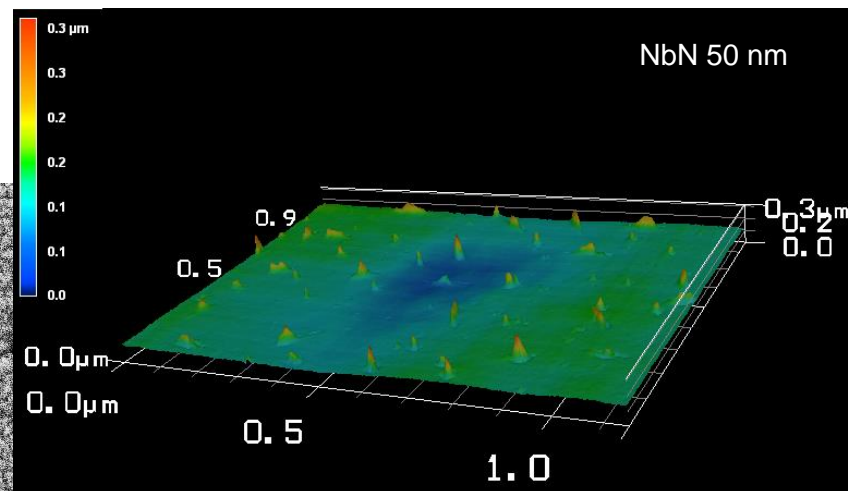
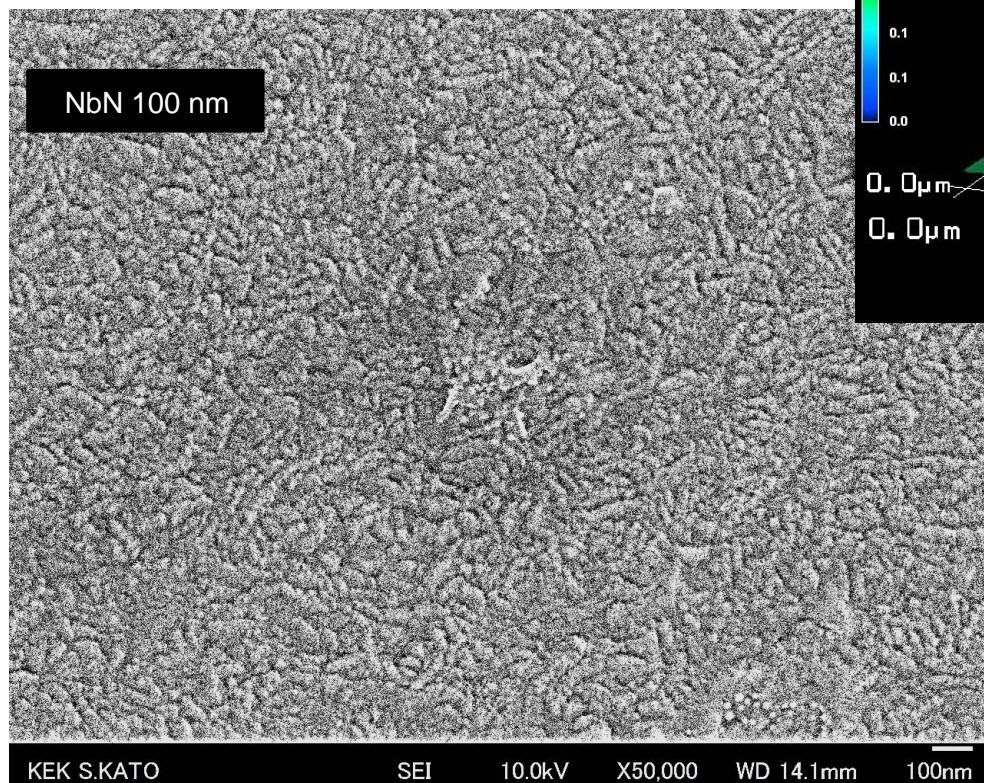


~ 18 mT
As expected for MS samples



Morphology

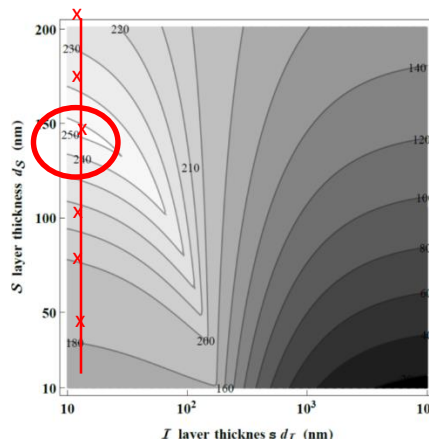
■ Rough surface



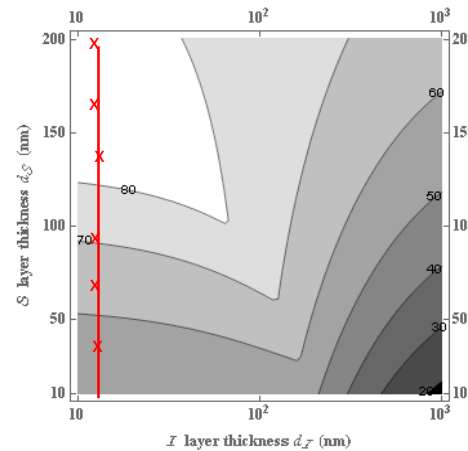
MgO needle ?
(capping material)

Theoretical predictions from T. Kubo (KEK)

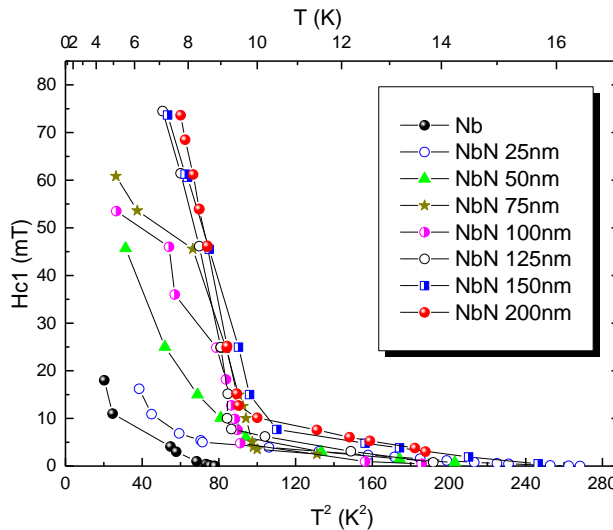
Ideal Nb substrate
with $B_{C1}=170 \text{ mT}$



Nb with defects*,
with $B_{C1}=50 \text{ mT}$



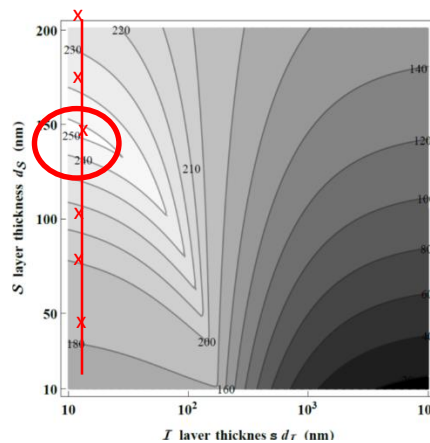
* e.g. morphologic
defects that allow earlier
vortex penetration See
SST paper cited earlier



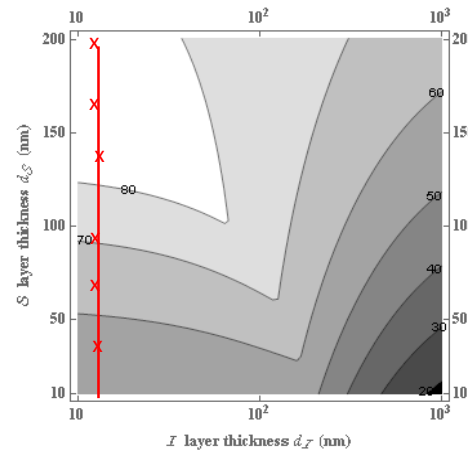
- The enhancement of the field penetration increases with thickness of NbN
- It reaches a saturation at thicknesses > 100 nm

Theoretical predictions from T. Kubo (KEK)

Ideal Nb substrate
with $B_{C1}=170$ mT

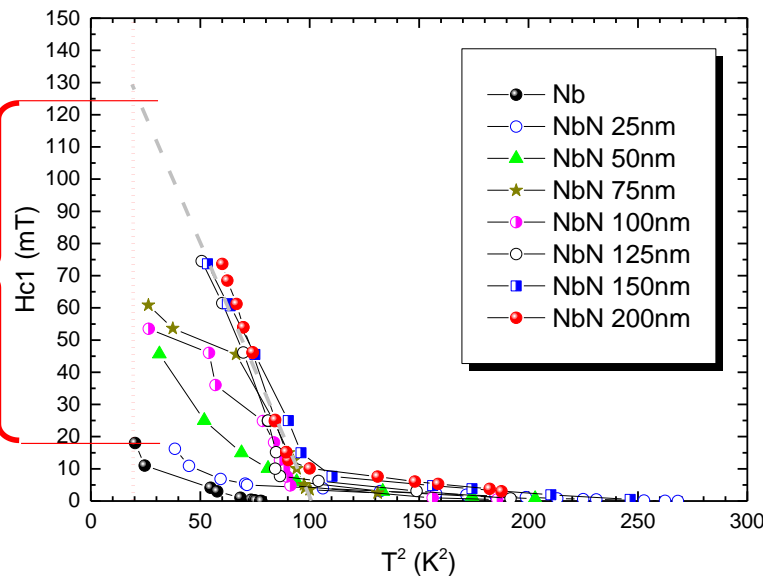


Nb with defects*,
with $B_{C1}=50$ mT



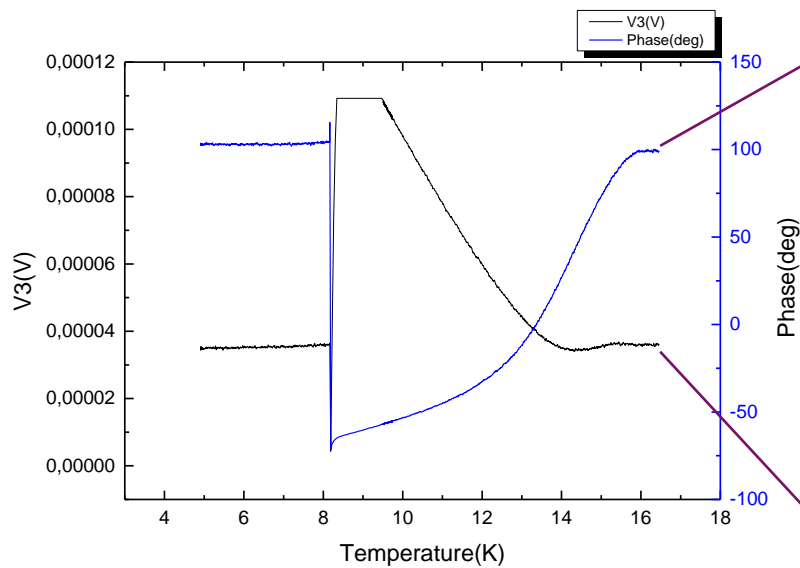
* e.g. morphologic
defects that allow earlier
vortex penetration See
SST paper cited earlier

@ 4.5 K
~ + 110 mT?
~25-30 MV/m
ILC shape

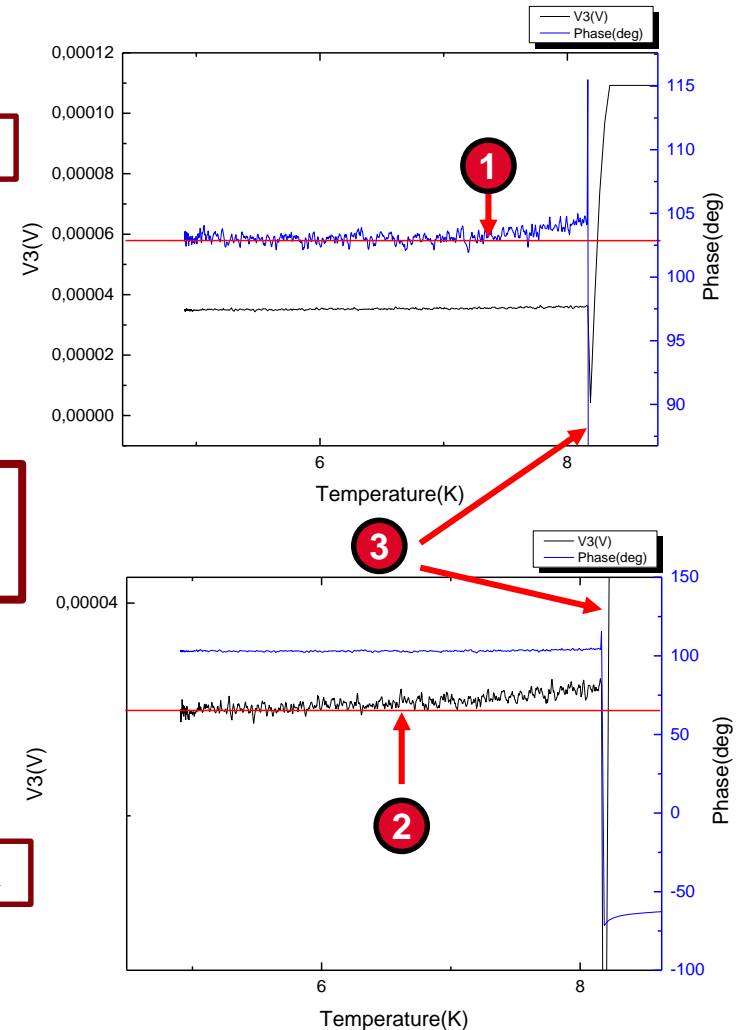


- The enhancement of the field penetration increases with thickness of NbN
- It reaches a saturation at thicknesses > 100 nm

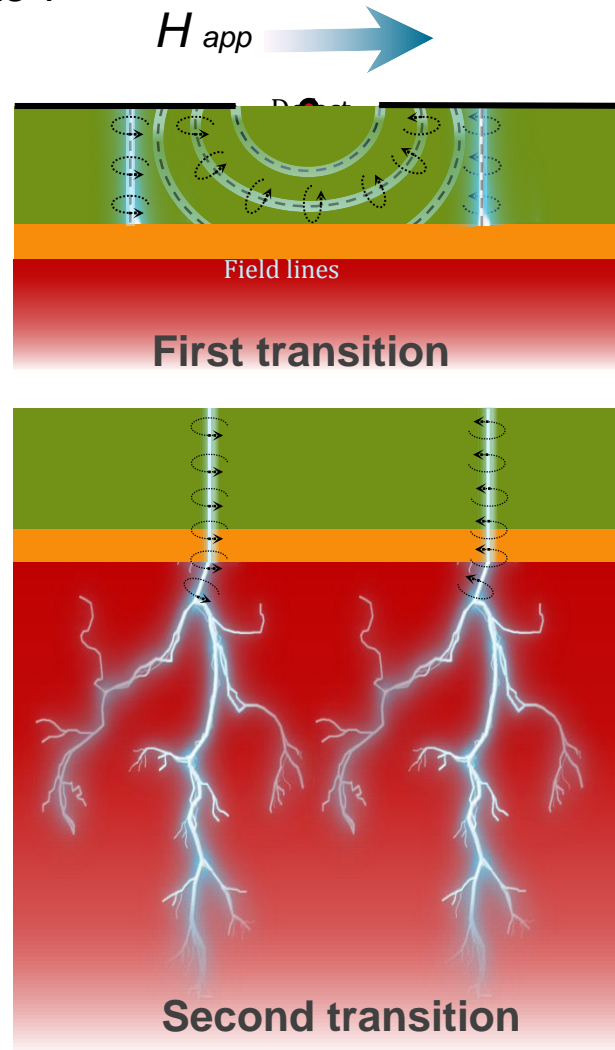
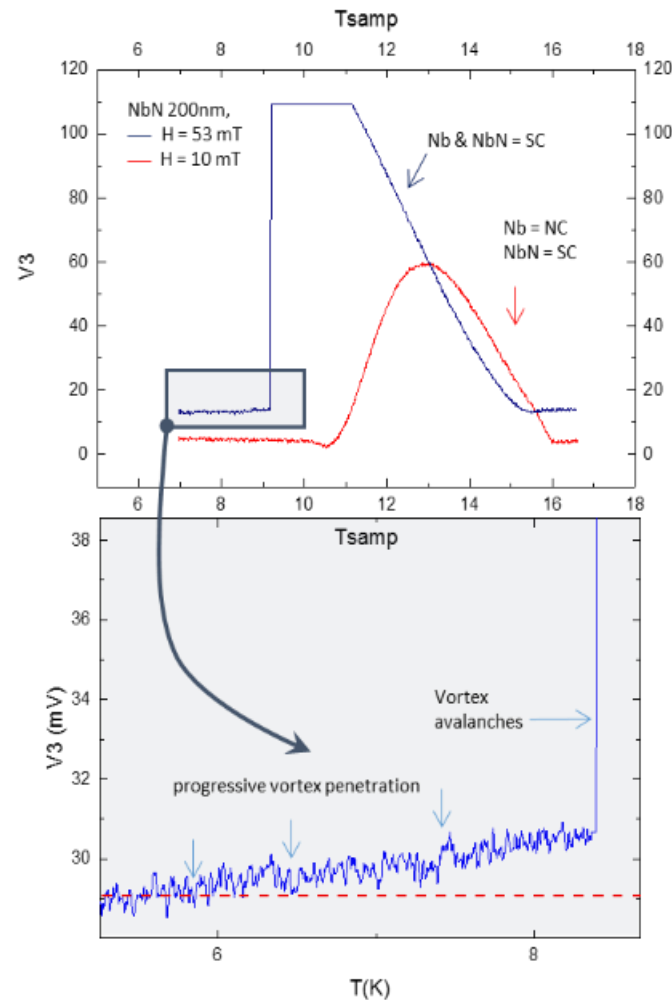
- For a given H_{appl} , we observe 3 \neq transition temperatures



- $T1 \sim T2$: within noise level
- $T3 \gg T2$: dramatic transition



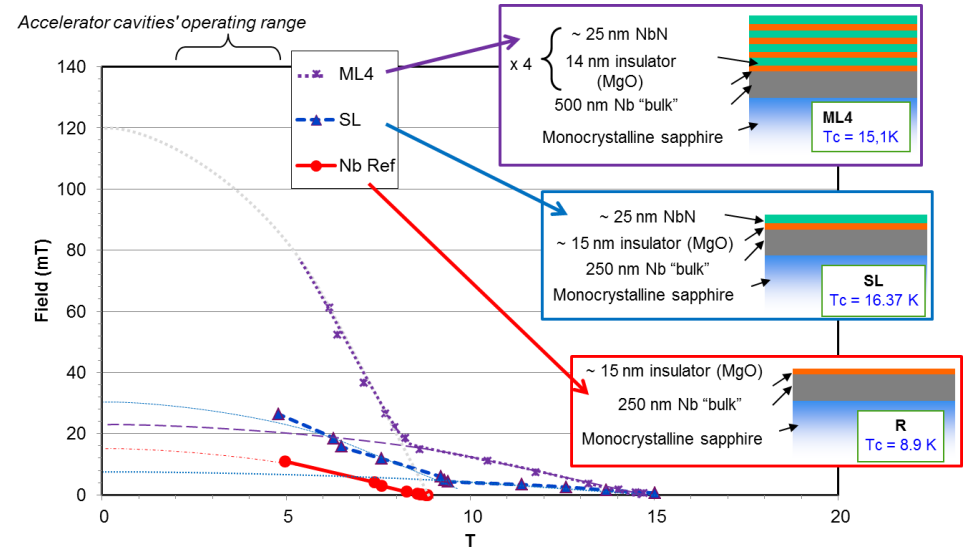
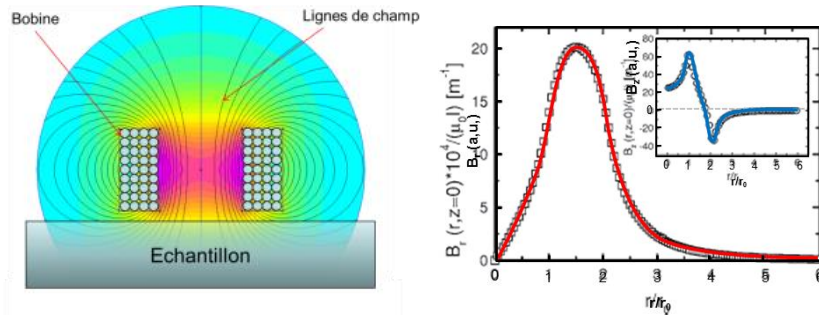
Why do we have two transitions ?



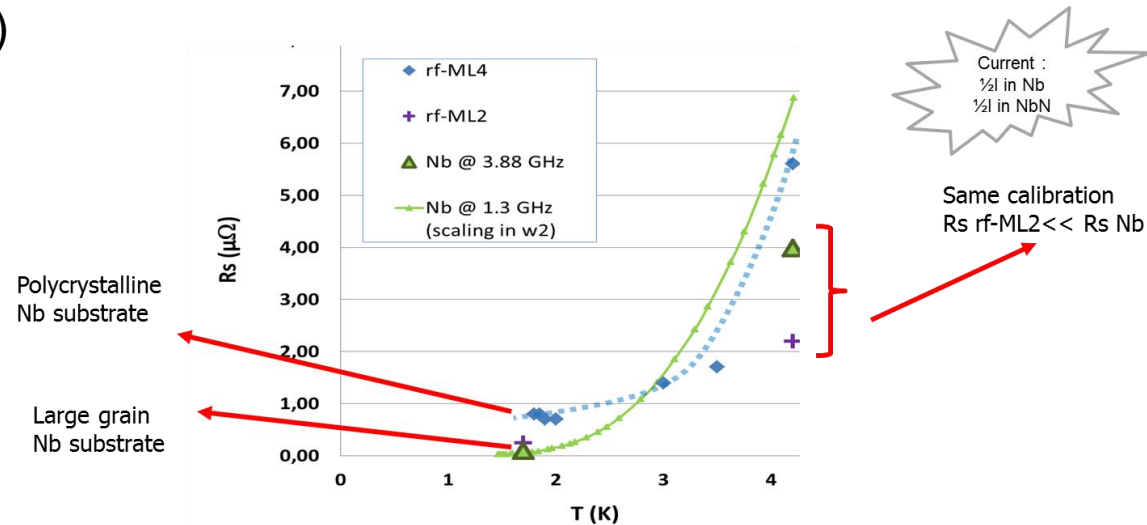
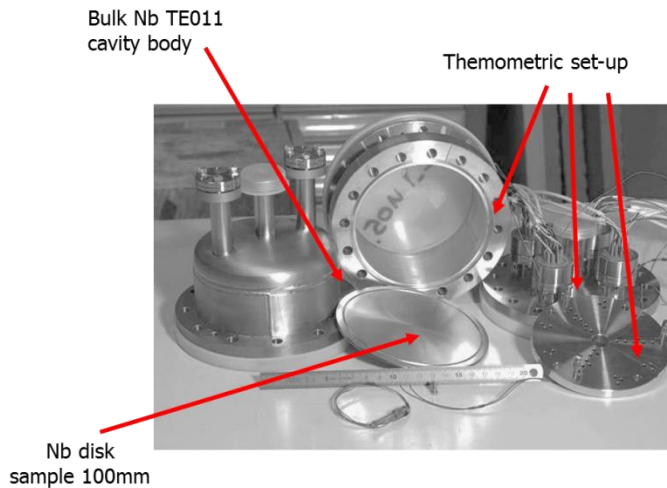
- Thin SC layer NbN
- Insulator MgO
- Thick SC layer Nb

- $H \parallel \text{surface} \Rightarrow \text{surface barrier}^\dagger$
- A defect locally weakens the surface barrier
- 1st transition, vortex blocked by the insulator ~ 100 nm \Rightarrow low dissipation.
- 2nd transition, propagation of vortex avalanches (~ 100 μm) \Rightarrow high dissipation.
- **Dielectric layer = efficient protection !!!**

Local magnetometry:



RF test (collaboration IPNO)



■ Scientifically:

- Very challenging upstream, discovery, R&D
- Efficiency of multilayer concept demonstrated
 - Field enhancement => higher SRF performances
 - Protection against “avalanches” => can accommodate defective (real) material
- Results close from theory => will help optimization

■ Future :

- Developing deposition techniques e.g. ALD, ECR, HPIMS....
- Up-grade of existing Nb cavities

■ Change of paradigm in SRF technology at hand

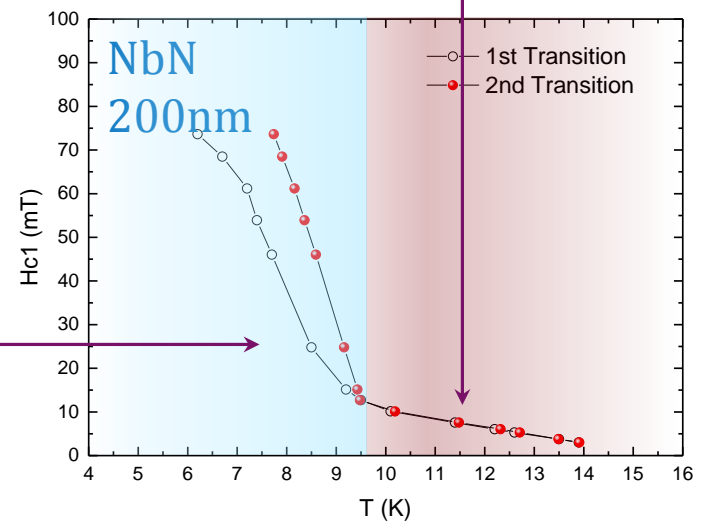
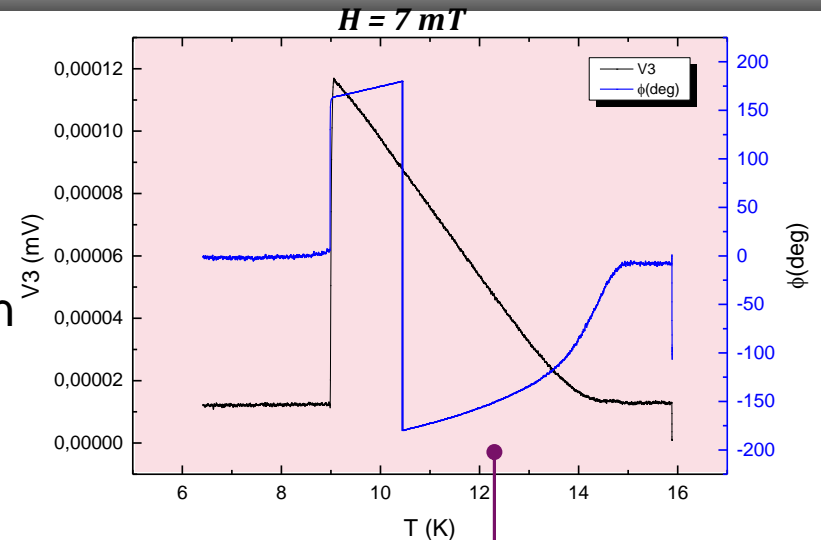
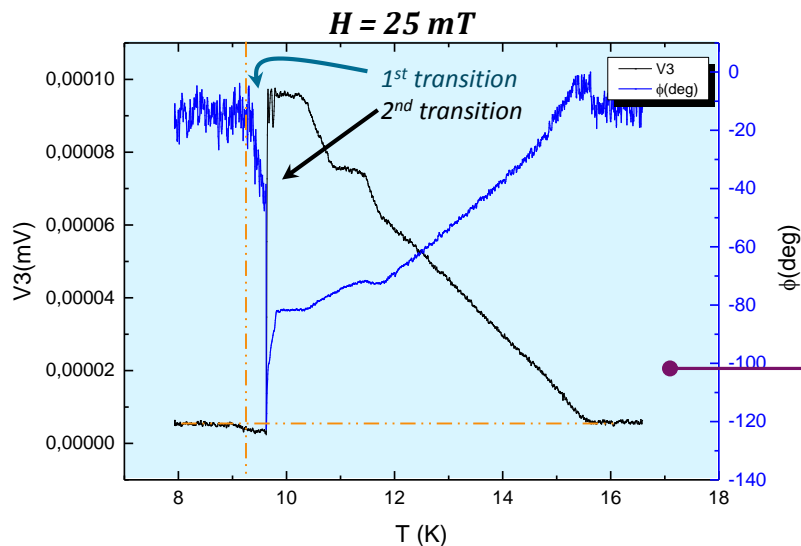
THANK YOU FOR YOUR ATTENTION



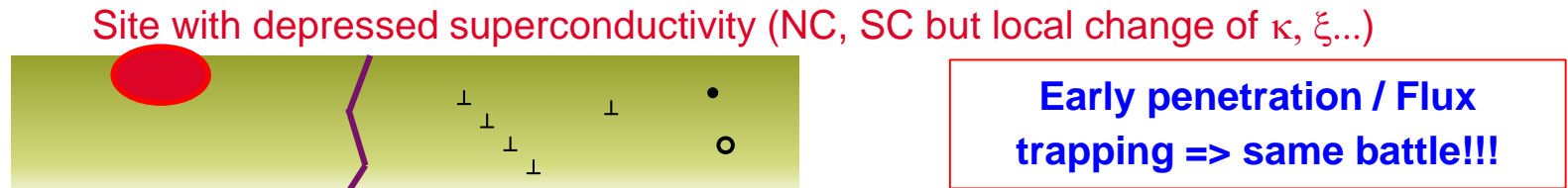
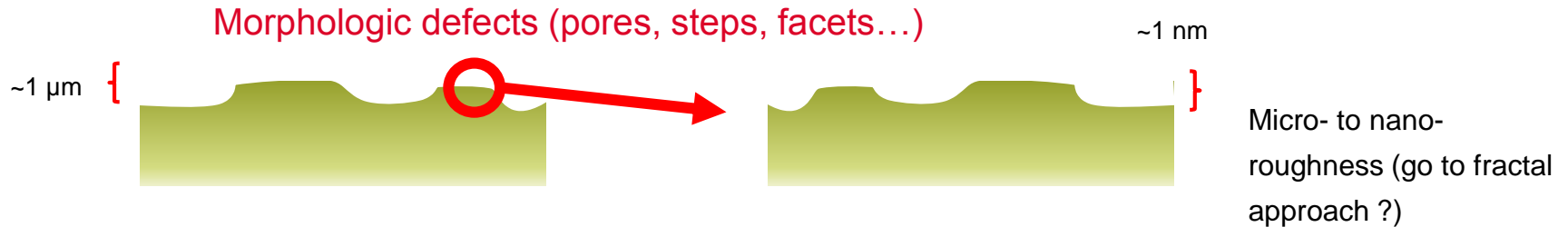
What do we measure ?



- Determination of H_{c1}
 - Low field => one transition
 - High field => two transitions
 - » 1st transition with low dissipation
 - » 2nd transition very strong dissipation
- Why do we have two transitions ?

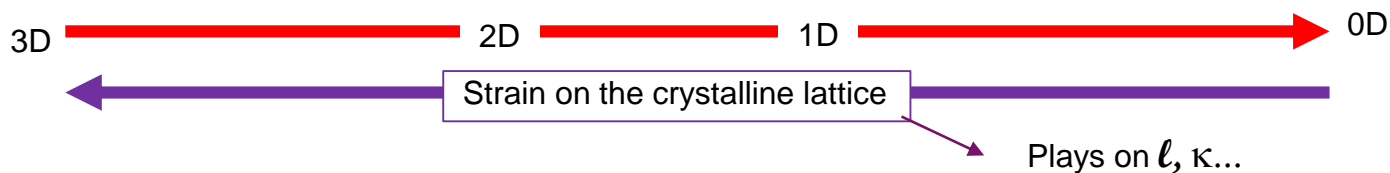


WHAT KIND OF DEFECTS ?



Crystalline defects :

Interfaces (inclusions) > GB > \perp cells > \perp (=dislocations) > vacancies or interstitials

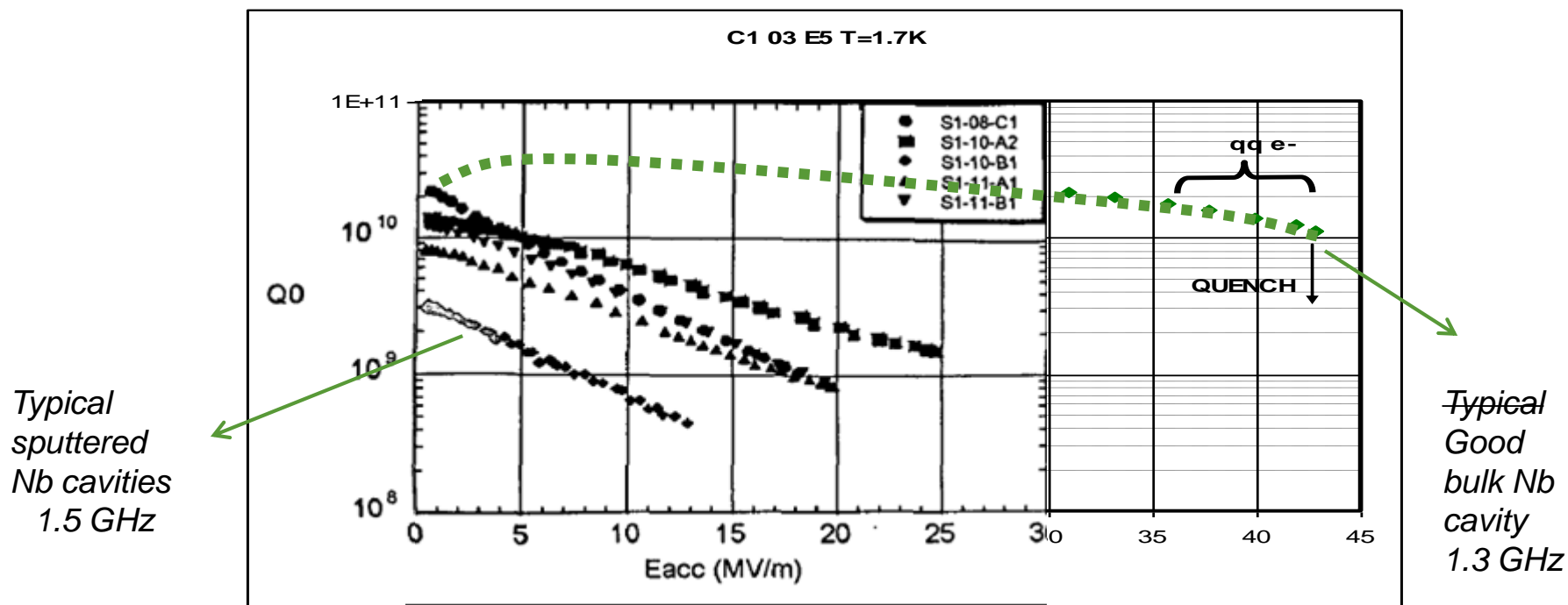


■ Bulk Niobium:

- grains $\varnothing > \sim 50 \mu\text{m}$ to mms, good crystallographic quality

■ Niobium $\sim 1\text{-}5 \mu\text{m}$ /Copper :

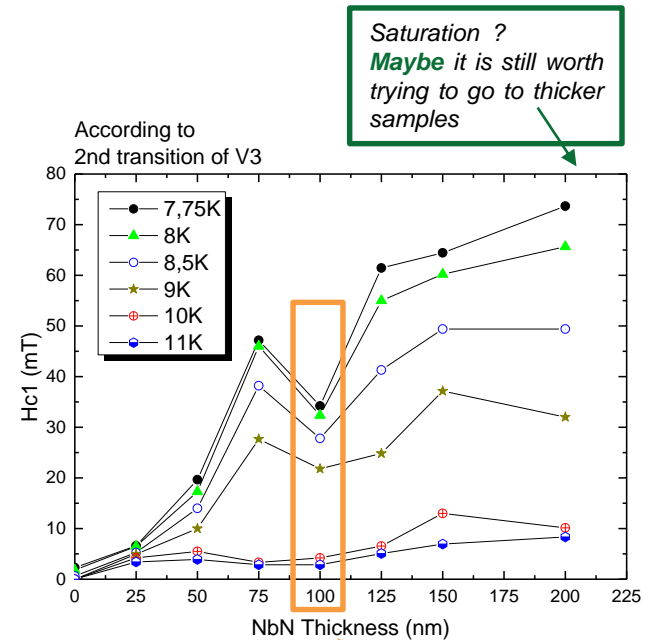
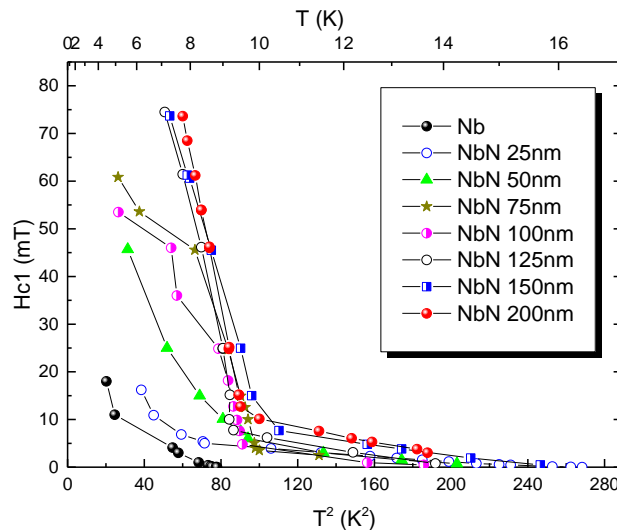
- $\varnothing < \sim 100 \text{ nm}$, many crystallographic defects, grain boundaries...
- sometimes better low field performance (thermal configuration and/or cost)



■ It is changing !!!: New emerging thin films techniques

Transition field (H_{SH} here ?)

- NbN single layers series
- NbN SL / “thick” Nb layer
- Magnetron sputtered
- MgO as dielectric layer



Saturation ?
Maybe it is still worth trying to go to thicker samples

According to
2nd transition of V3

Maybe this sample quality is not good !

- The enhancement of the field penetration increases with thickness of NbN
- It reaches a saturation at thicknesses > 100 nm